

TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE (π -MOSIII)

2SK2719

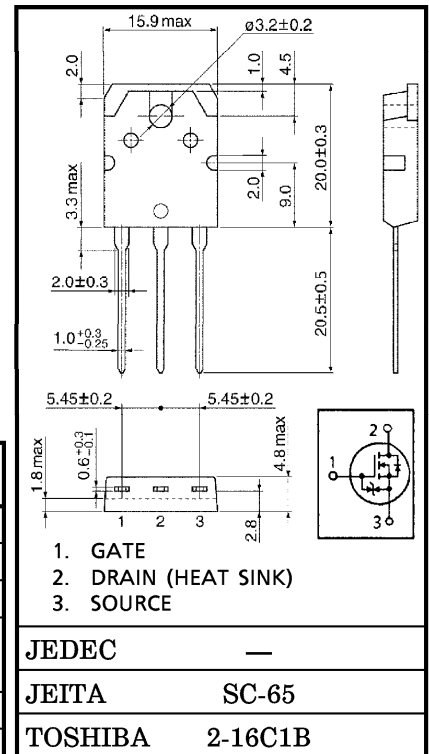
CHOPPER REGULATOR, DC-DC CONVERTER AND MOTOR DRIVE APPLICATIONS

- Low Drain-Source ON Resistance : $R_{DS(ON)} = 3.7 \Omega$ (Typ.)
- High Forward Transfer Admittance : $|Y_{fs}| = 2.6 S$ (Typ.)
- Low Leakage Current : $I_{DSS} = 100 \mu A$ (Max.) ($V_{DS} = 720 V$)
- Enhancement-Mode : $V_{th} = 2.0 \sim 4.0 V$
($V_{DS} = 10 V, I_D = 1 mA$)

MAXIMUM RATINGS ($T_a = 25^\circ C$)

CHARACTERISTIC		SYMBOL	RATING	UNIT
Drain-Source Voltage		V_{DSS}	900	V
Drain-Gate Voltage ($R_{GS} = 20 k\Omega$)		V_{DGR}	900	V
Gate-Source Voltage		V_{GSS}	± 30	V
Drain Current	DC (Note 1)	I_D	3	A
	Pulse (Note 1)	I_{DP}	9	
Drain Power Dissipation ($T_c = 25^\circ C$)		P_D	125	W
Single Pulse Avalanche Energy (Note 2)		E_{AS}	295	mJ
Avalanche Current		I_{AR}	3	A
Repetitive Avalanche Energy (Note 3)		E_{AR}	12.5	mJ
Channel Temperature		T_{ch}	150	$^\circ C$
Storage Temperature Range		T_{stg}	$-55 \sim 150$	$^\circ C$

Unit in mm



Weight : 4.6 g (Typ.)

THERMAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance, Channel to Case	$R_{th(ch-c)}$	1.0	°C/W
Thermal Resistance, Channel to Ambient	$R_{th(ch-a)}$	50.0	°C/W

(Note 1) : Please use devices on condition that the channel temperature is below 150°C.

(Note 2) : $V_{DD} = 25\text{ V}$, $T_{ch} = 25^\circ\text{C}$ (initial), $L = 58\ \mu\text{H}$, $R_G = 25\ \Omega$, $I_{AR} = 45\ \text{A}$

(Note 3) : Repetitive rating ; Pulse Width Limited by maximum junction temperature.

**This transistor is an electrostatic sensitive device.
Please handle with caution.**

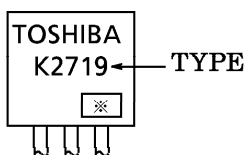
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		I_{GSS}	$V_{GS} = \pm 30\text{ V}, V_{DS} = 0\text{ V}$	—	—	± 10	μA
Gate-Source Breakdown Voltage		$V_{(BR)GSS}$	$I_G = \pm 10\ \mu\text{A}, V_{DS} = 0\text{ V}$	± 30	—	—	V
Drain Cut-off Current		I_{DSS}	$V_{DS} = 720\text{ V}, V_{GS} = 0\text{ V}$	—	—	100	μA
Drain-Source Breakdown Voltage		$V_{(BR)DSS}$	$I_D = 10\text{ mA}, V_{GS} = 0\text{ V}$	900	—	—	V
Gate Threshold Voltage		V_{th}	$V_{DS} = 10\text{ V}, I_D = 1\text{ mA}$	2.0	—	4.0	V
Drain-Source ON Resistance		$R_{DS(ON)}$	$V_{GS} = 10\text{ V}, I_D = 1.5\text{ A}$	—	3.7	4.3	Ω
Forward Transfer Admittance		$ Y_{fs} $	$V_{DS} = 20\text{ V}, I_D = 1.5\text{ A}$	0.65	2.6	—	S
Input Capacitance		C_{iss}	$V_{DS} = 25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1\text{ MHz}$	—	750	—	pF
Reverse Transfer Capacitance		C_{rss}		—	10	—	
Output Capacitance		C_{oss}		—	70	—	
Switching Time	Rise Time	t_r		—	15	—	ns
	Turn-on Time	t_{on}		—	55	—	
	Fall Time	t_f		—	30	—	
	Turn-off Time	t_{off}		Duty $\leq 1\%$, $t_w = 10\ \mu\text{s}$	—	110	
Total Gate Charge (Gate-Source Plus Gate-Drain)		Q_g	$V_{DD} \doteq 400\text{ V}, V_{GS} = 10\text{ V},$ $I_D = 3\text{ A}$	—	25	—	nC
Gate-Source Charge		Q_{gs}		—	13	—	
Gate-Drain (“Miller”) Charge		Q_{gd}		—	12	—	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Continuous Drain Reverse Current (Note 1)	I_{DR}	—	—	—	3	A
Pulse Drain Reverse Current (Note 1)	I_{DRP}	—	—	—	9	A
Diode Forward Voltage	V_{DSF}	$I_{DR} = 3\text{ A}, V_{GS} = 0\text{ V}$	—	—	-1.9	V
Reverse Recovery Time	t_{rr}	$I_{DR} = 3\text{ A}, V_{GS} = 0\text{ V}$ $dI_{DR}/dt = 100\text{ A}/\mu\text{s}$	—	1100	—	ns
Reverse Recovery Charge	Q_{rr}		—	7.5	—	μC

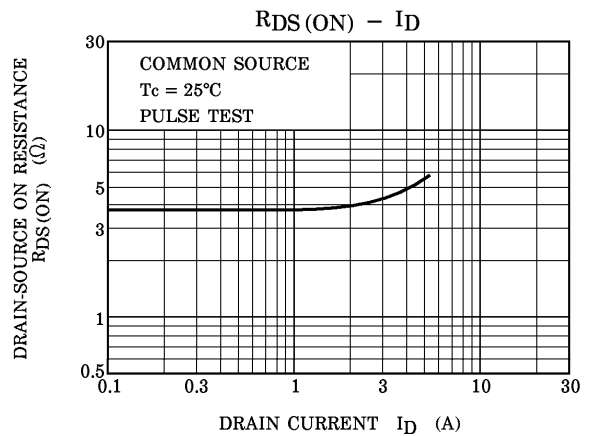
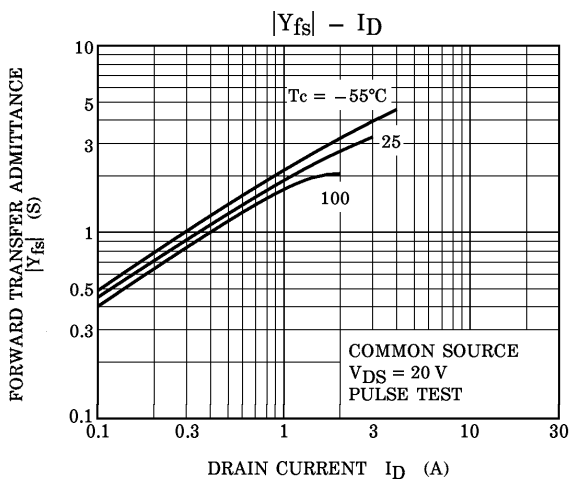
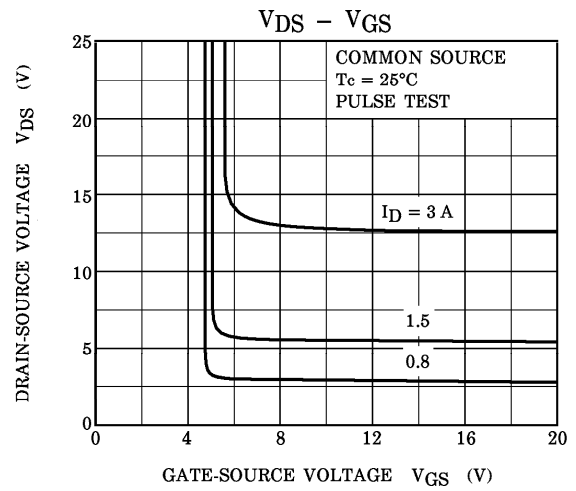
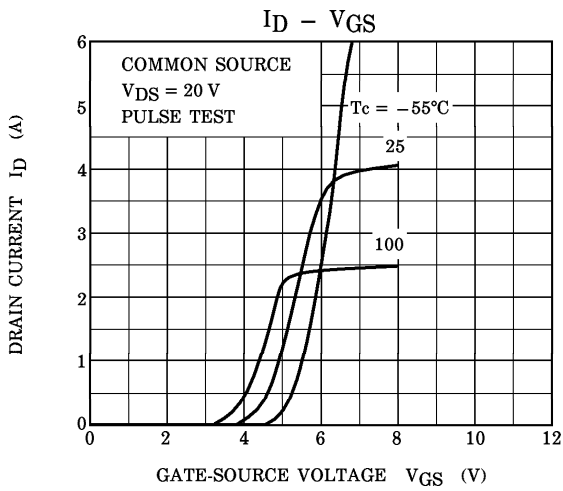
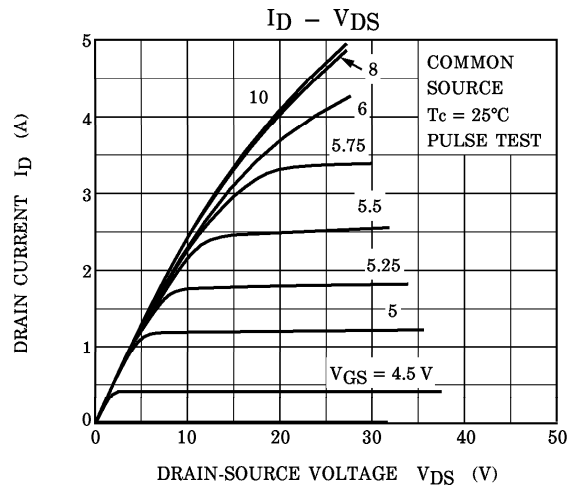
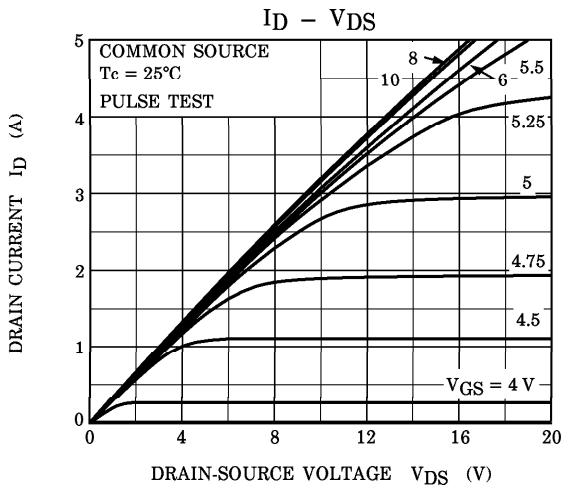
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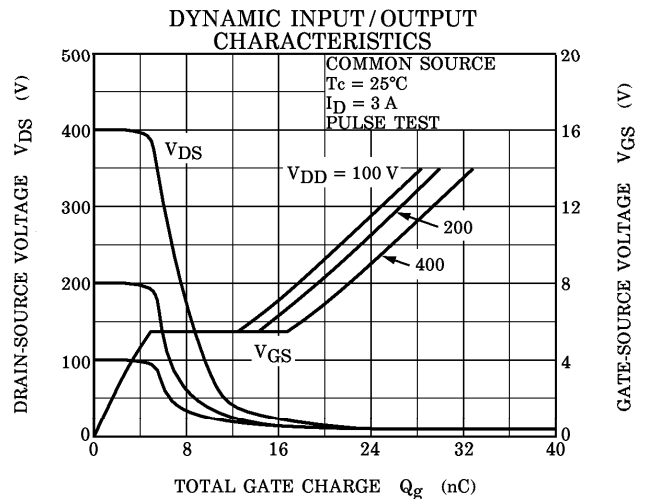
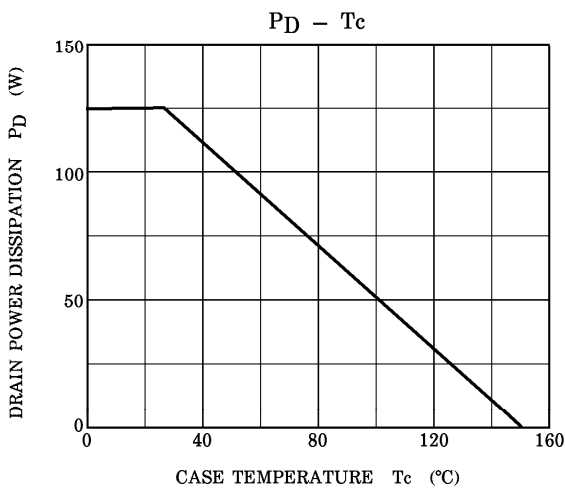
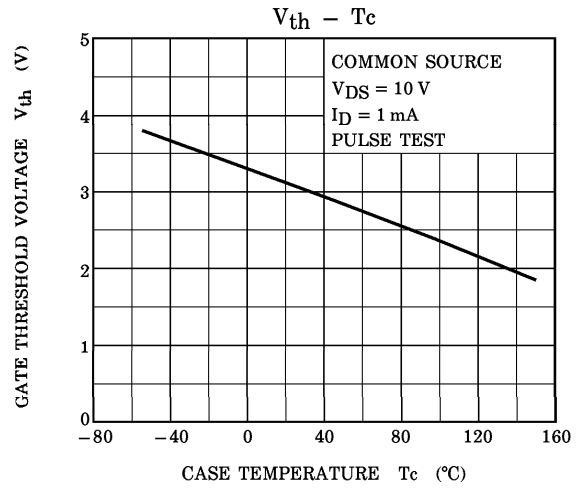
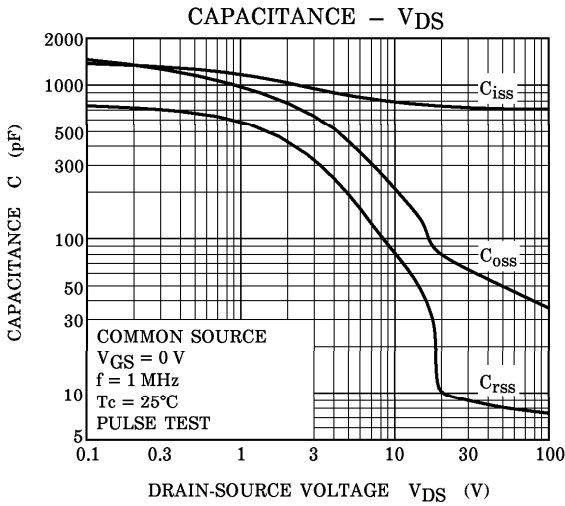
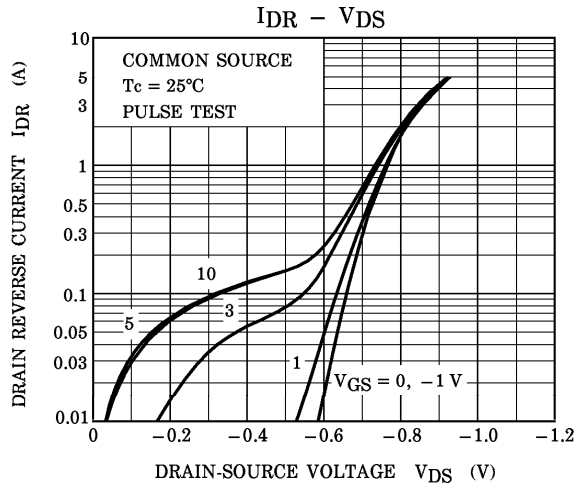
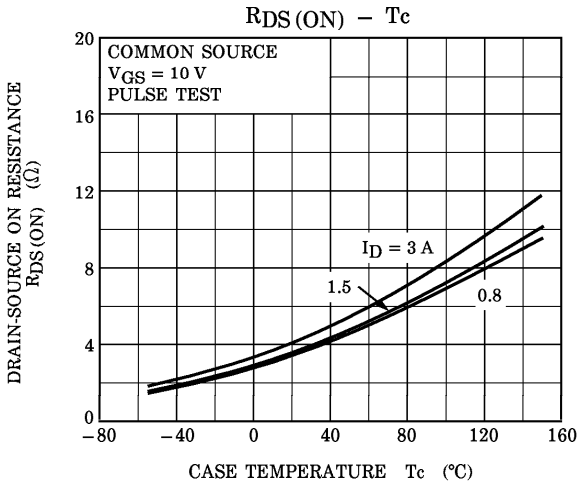


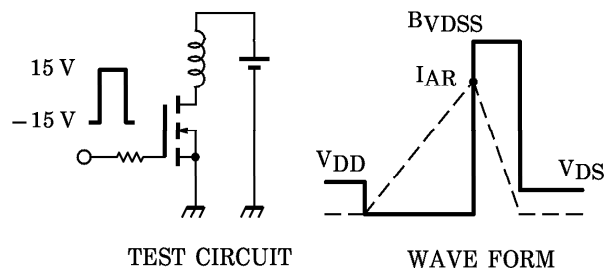
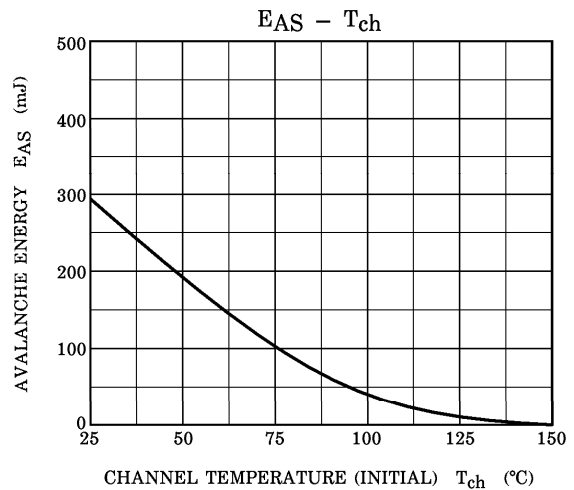
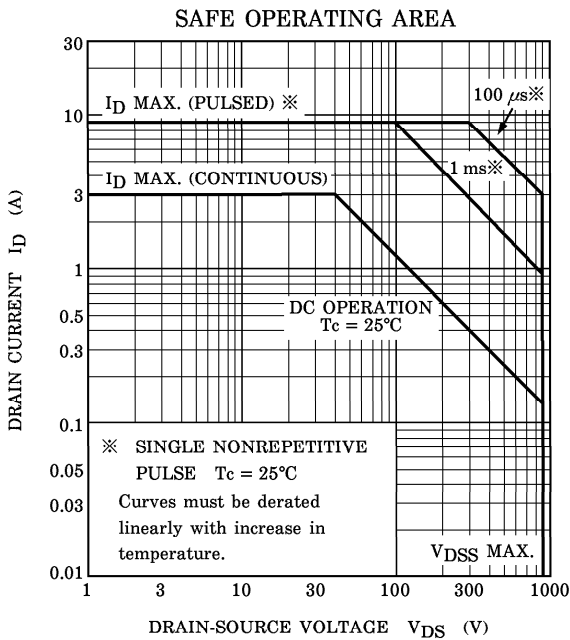
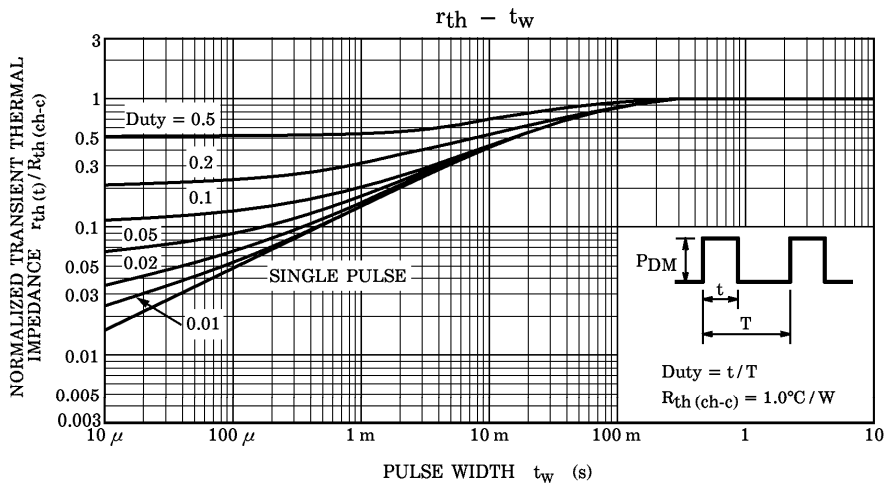
※ Lot Number

□ □ — Month (Starting from Alphabet A)

— Year (Last Number of the Christian Era)







$R_G = 25 \Omega$
 $V_{DD} = 90 V, L = 60 mH$

$$EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

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